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12/426,694	04/21/2009	Jerrardo Prieto	4384-000111	6106
7950 09/09/2011 Harness, Dickey & Pierce, P.L.C. P.O. Box 828 Bloomfield Hills, MI 48303				
			EXAMINER RICHIE, SCOTT M	
			ART UNIT 2877	PAPER NUMBER
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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Page 7

Although the claims are laden with grammatical and clarity issues, in the interest of compact prosecution, the examiner's broadest reasonable interpretations are provided below in light of the prior art.

***Claim Rejections - 35 USC § 102***

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

*A person shall be entitled to a patent unless --*

*(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.*

Claims 1-8, 10, and 12-16 are rejected under 35 U.S.C. 102(b) as being anticipated by

U.S. Patent No. 6,577,403 ("Primot")

Primot discloses a method for analyzing the wave surface of a light beam in optical control, the method comprising:

(Claim 1) a phase function introduced by a two-dimensional grating substantially positioned in a plane perpendicular to the light beam to be analyzed and optically conjugated of the plane of analysis of the wave surface, which causes a diffraction of the beam into various emerging beams (Col. 5); an intensity function (Col. 5); deformations of an image related to gradients of the analyzed wave surface, such image being formed by the interference of emerging beams and being created and viewed in a plane located at a chosen distance from the grating plane (Col. 3); with the intensity function being uniform on the whole surface of the grating, the step includes the multiplication: of a first phase function, the exclusion function, which defines a meshing of useful zones, which introduces no phase spatial variations in the transmission or the reflection of the light of the analyzed beam, and exclusion zones introducing